# Abstracts

## Small-Signal RF Yield Analysis of MMIC Circuits Based on Physical Device Parameters

*D.L. Allen, J. Beall and M. King. "Small-Signal RF Yield Analysis of MMIC Circuits Based on Physical Device Parameters." 1992 MTT-S International Microwave Symposium Digest 92.3 (1992 Vol. III [MWSYM]): 1473-1476.*

This paper describes a technique for computing small-signal RF yield of monolithic microwave integrated (MMIC) circuits based on the sensitivity of electrical model parameters to physical device parameters. Because GaAs MMICs are increasingly being used in large scale production programs, the producibility of a given design must be considered at the beginning of the design process. The RF yield analysis approach to be described uses key MMIC device physical variables and computed sensitivities of electrical model parameters to those variables.

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